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11-28-03

Docket No.: M4065.0215/P215  
(PATENT)

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of:  
Eugene A. DeLaRosa, et al.

Application No.: 09/516,581

Art Unit: 2621

Filed: March 1, 2000

Examiner: B. Werner

For: METHOD FOR MEASURING  
REGISTRATION OF OVERLAPPING  
MATERIAL LAYERS OF AN  
INTEGRATED CIRCUIT

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**AMENDMENT IN RESPONSE TO NON-FINAL OFFICE ACTION**

MS Non-Fee Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

**INTRODUCTORY COMMENTS**

In response to the Office Action dated August 19, 2003 (Paper No. 6), please amend the above-identified U.S. patent application as follows:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 8 of this paper.

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